

Application/Control No.	Applicant(s)/Patent under Reexamination								
10/643,825	HULL ET AL.								
Examiner	Art Unit								
Dienane M. Bayard	2141								

							Djenane W. Bayard						2141							
							10	2011	EC	Λς	SIFI	$C\Lambda^{T}$	TION.				-			
			OBIGIN			₁	13	<u> </u>		LAS	SIFI			-	NCE(S)					
ORIGINAL							CROSS REFERENCE(S) SUBCLASS (ONE SUBCLASS PER BLOCK)													
CLASS SUBCLASS CLASS						1														
709 206 709				201									- 							
INTERNATIONAL CLASSIFICA			CATION		715		00								ļ.		ļ			
G	0	6	F	15/16			358		02											
						T														
	 ', 			\dashv					<u> </u>						1					
			╬									+		1		+				
								-							+		+		-	
				/				1	4_	-	4								1	
Genani Bayand 9/20/07 (Assistant Examiner) (Date)						Vsi	Vin Jan								Total Claims Allowed: 19					
						SUPERVISORY PATER TECHNOLOGY CENTER 210(Pate) (Primary Examiner) 7 2 3000							O.G. Print Claim(s)			O.G. Print Fig.				
(Legal Instruments Examiner) (Date)							(Primary Examiner) LR 210(Date)							21			2			
														+-/			-	1		
L	Claims renumbered in the same orde					er as presented by applicant 🔲 🗀						PA	▼ T.D.				☐ R.1.47			
i	Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original
		1	1	11	31			61			91			121			151			181
_		2		12	32			62			92			122			152			182
		3]	13	33			63			93			123			153			183
		4		14	34			64			94	,		124	-		154			184
	_	5	4	15	35			65			95			125	-		155			185
		6_	-	16	36			66 67			96 97			126 127	-		156 157			186
	_	7 8	-	17	37 38			68			98			128	-		158			188
		9	-	19	39			69			99			129	-		159			189
	\dashv	10	-	"	40		—	70			100			130	ŀ		160			190
		11	1		41			71			101			131	Ī		161			191
		12			42			72			102			132			162			192
		13] .		43			73			103			133			163			193
		14			44			74			104			134			164			194
			_																	
		15]		45			75			105			135	-		165			195